



NABL

National Accreditation Board for Testing and Calibration Laboratories

(An Autonomous Body under Department of Science & Technology, Govt. of India)

CERTIFICATE OF ACCREDITATION

INSTITUTE OF TESTING AND CERTIFICATION (INDIA) PVT. LTD.

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2005

"General Requirements for the Competence of Testing & Calibration Laboratories"

for its facilities at

362, Industrial Area, Phase-II, Panchkula, Haryana

in the discipline of

ELECTRONICS TESTING

(To see the scope of accreditation of this laboratory, you may also visit NABL website www.nabl-india.org)

Certificate Number T-3509

Issue Date 21/07/2015



Valid Until 05/05/2017

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the additional requirements of NABL.

Signed for and on behalf of NABL

N. Venkateswaran
Program Manager

Anil Relia
Director

Prof. S. K. Joshi
Chairman



रा.प्र.प्र.बो.

राष्ट्रीय परीक्षण और अंशशोधन प्रयोगशाला प्रत्यायन बोर्ड

(विज्ञान एवं प्रौद्योगिकी विभाग, भारत सरकार के अधीन स्वायत्तशासी निकाय)

प्रत्यायन प्रमाण-पत्र

इंस्टिट्यूट ऑफ टेस्टिंग एंड सर्टिफिकेशन (इंडिया) प्रा. लि.

का मूल्यांकन और प्रत्यायन निम्न मानक के अनुसार

आई.एस.ओ./आई.ई.सी. 17025:2005

“परीक्षण एवं अंशशोधन प्रयोगशालाओं की सक्षमता की सामान्य अपेक्षाएँ”

पंचकुला, हरियाणा

में स्थित इसकी सुविधाओं के लिए

इलेक्ट्रॉनिक्स परीक्षण

के विषय क्षेत्र में किया गया।

(इस प्रयोगशाला के प्रत्यायन के विषय क्षेत्र की जानकारी एन ए बी एल वेबसाइट www.nabl-india.org से भी प्राप्त कर सकते हैं)

प्रमाण-पत्र संख्या प - 3509

जारी करने की तिथि 21/07/2015



वैधता की तिथि 05/05/2017

यह प्रमाण-पत्र उपर्युक्त मानक तथा राष्ट्रीय परीक्षण और अंशशोधन प्रयोगशाला प्रत्यायन बोर्ड की अतिरिक्त अपेक्षाओं का निरंतर संतोषप्रद अनुपालन किए जाने पर अनुबंध में निर्दिष्टानुसार प्रत्यायन के क्षेत्र के लिए वैध रहेगा।

रा.प्र.प्र.बो. की ओर से हस्ताक्षरित

एन. वेंकटेश्वरन

अनिल रेलिया

श्रीकृष्ण जोशी

एन. वेंकटेश्वरन
कार्यक्रम प्रबन्धक

अनिल रेलिया
निदेशक

प्रो. श्रीकृष्ण जोशी
अध्यक्ष



NABL

SCOPE OF ACCREDITATION

Laboratory	Institute of Testing and Certification (India) Pvt. Ltd, 362, Industrial Area, Phase-II, Panchkula, Haryana		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electronics Testing	Issue Date	21.07.2015
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Last Amended on	-	Page	1 of 3

S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
I. MEDICAL ELECTRICAL EQUIPMENT				
1.	Medical Devices	Power Input	IEC 60601-1 :2005 Cl.4.11 IEC 60601-1 Ed.3, 2005-12 IS 13450-1: 2008	0 to 300 V AC (at 50 Hz), 0 to 19.99 A
		Marking & Instruction	IEC 60601-1:2005 Cl.7	Qualitative Test
		Determination of Accessible Parts	IEC 60601-1:2005 Cl.5.9	0 to 60 V
		Protective earthing, functional earthing and potential equalization of me Equipment	IEC 60601-1:2005 Cl.8.6	1A to 30 A, 0 to 19.99V
		Leakage currents and patient auxiliary currents	IEC 60601-1:2005 Cl.8.7	50 μ A to 20 m A
		Dielectric Strength	IEC 60601-1:2005 Cl.8.8.3	0 to 5 kV
		Resistance to environmental stress	IEC 60601-1:2005 Cl.8.8.4.2	0 to 250 $^{\circ}$ C/ Dia. Impression 0 to 10mm
		Accessible Parts Including Applied Part	IEC 60601-1:2005 Cl.5.9	(dia 4 mm, L 100mm)
		Creepage distances and air clearances	IEC 60601-1:2005 Cl.8.9	0 to 150 mm
		Instability hazards	IEC 60601-1:2005 Cl.9.4	Qualitative Test CTIT (0 to 700 V AC) (50 Hz) 0 to 90 $^{\circ}$


Dheeraj Chawla
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N. Venkateswaran
Program Manager



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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Medical Devices	Overflow, spillage, leakage ingress of water or particulate matter, cleaning, disinfection, sterilization and compatibility with substances used with ME equipment	IEC 60601-1 :2005 Cl.11.6	Qualitative
II.	IT EQUIPMENT			
1.	Information Technology Equipments (Monitor, SMPS, Network Card, UPS, Computer, Modem, Cable Tester, Balance, Refrigerated Enclosure)	List of critical components	IEC 60950-1:2005 Cl.1.5.1 IEC 60950-1:2005-12 Ed-2.	Qualitative Test
		Electrical data	IEC 60950-1:2005 Cl.1.6.2	0 to 300V AC (at 50Hz), 0 to 19.99 A
		Durability	IEC 60950-1:2005 Cl.1.7.11	Qualitative Test
		Access to energized parts	IEC 60950-1:2005 Cl. 2.1.1.1	30 N 4 mm, 3 mm, 5 mm 12 mm & 80 mm
		Limited power source measurement	IEC 60950-1:2005 Cl.2.5	0 to 300 V 0 to 19.9A
		Resistance to earthing conductors	IEC 60950-1:2005 Cl. 2.6.3.4	1 A to 30 A, 0 to 19.99V
		Humidity conditioning	IEC 60950-1:2005 Cl. 2.9.2	20 °C to 30 °C 91 % to 95 % R.H
		Clearances, creepage distances and distances through insulation	IEC 60950-1:2005 Cl. 2.10	0 to 150 mm

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	Information Technology Equipments (Monitor, SMPS, Network Card, UPS, Computer, Modem, Cable Tester, Balance, Refrigerated Enclosure)	Stability	IEC 60950-1:2005 Cl. 4.1	0 to 90 °
		Drop test	IEC 60950-1:2005 Cl. 4.2.6	Qualitative Test
		Stress relief	IEC 60950-1:2005 Cl. 4.2.7	25 °C to 250 °C (70 K over normal temperature)
		Protection against hazardous moving parts	IEC 60950-1:2005 Cl. 4.4	30 N
		Maximum temperatures	IEC 60950-1:2005 Cl.4.5.1	(-) 100 °C to 550 °C
		Resistance to abnormal heat	IEC 60950-1:2005 Cl. 4.5.5	0 to 250 °C/ Dia. Impression 0 to 10 mm
		Enclosure openings	IEC 60950-1:2005 Cl.4.6.1 & 4.6.2	Qualitative Test
		Touch current and protective conductor current	IEC 60950-1:2005 Cl. 5.1	50 µA to 20 m A
		Electric strength	IEC 60950-1:2005 Cl. 5.2	0 to 5 kV
		Fault conditions tests	IEC 60950-1:2005 Cl.5.3	Qualitative Test
	Impulse test	IEC 60950-1:2005 Cl. 6.2.2.1 & 6.2.2.2	0 to 10 KV	

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